

•General Description

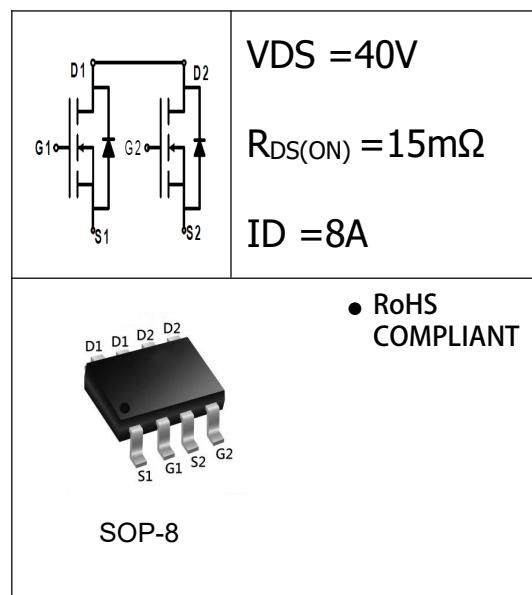
The LH4882A uses trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. This device is suitable for high current load applications.

•Features

- Advance high cell density trench technology
- Low RDS(ON) to minimize conductive loss
- Low Gate Charge for fast switching

•Application

- Lighting
- Power Supplies
- PD Fast Charging



•Ordering Information:

Part Number	LH4882A
Package	SOP-8
Basic Ordering Unit (pcs)	4000
Normal Package Material Ordering Code	LH4882AS-SOP8-TAP
Halogen Free Ordering Code	LH4882AS-SOP8-TAP-HF

•Absolute Maximum Ratings ($T_C = 25^\circ C$)

PARAMETER	SYMBOL	VALUE	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	40	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current, $T_C = 25^\circ C^1$	I_D	8	A
Continuous Drain Current, $T_C = 100^\circ C^1$	I_D	6	A
Pulsed drain current ($T_C = 25^\circ C$, t_p limited by T_{jmax}) ²	I_{DM}	36	A
Single Pulse Avalanche Energy ³	E_{AS}	11	mJ
Power Dissipation ⁴	$P_D(T_C=25^\circ C)$	1.9	W
Operating Temperature	T_J	-55~+150	°C
Storage Temperature	T_{STG}	-55~+150	°C

●N-Channel Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	40	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.5	2.5	V
Drain-source On Resistance ²	$R_{DS(ON)}$	$V_{GS}=10V, I_D=7A$	--	15	18	$m\Omega$
		$V_{GS}=4.5V, I_D=4A$	--	16.5	20	
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=32V, V_{GS}=0V, T_J=25^\circ C$	--	--	1	μA
		$V_{DS}=32V, V_{GS}=0V, T_J=55^\circ C$	--	--	5	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	--	--	± 100	nA
Forward Transconductance	G_{FS}	$V_{DS}=5V, I_D=7A$	--	33	--	S
Gate Resistance	R_g	$V_{DS}=0V, V_{GS}=0V, f=1MHz$	--	2.2	--	Ω
Continuous Diode Forward Current ^{1,5}	I_S	Force Current	--	--	2.5	A
Diode Forward Voltage ²	V_{SD}	$T_J=25^\circ C, I_S=1A, V_{GS}=0V$	--	0.7	--	V

DYNAMIC PARAMETERS

Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=15V, f=1.0MHz$	--	572	--	pF
Output Capacitance	C_{oss}		--	80	--	
Reverse transfer Capacitance	C_{rss}		--	65	--	

SWITCHING PARAMETERS

Total Gate Charge	Q_g	$I_D=7A, V_{DS}=15V, V_{GS}=4.5V$	--	6.0	--	nC
Gate-to-Source Charge	Q_{gs}		--	2.5	--	
Gate-to-Drain Charge	Q_{gd}		--	2.1	--	
Reverse Recovery Time	T_{rr}	$I_f=7A, di/dt=100A/us$	--	10	--	nS
Reverse Recovery Charge	Q_{rr}		--	3.3	--	

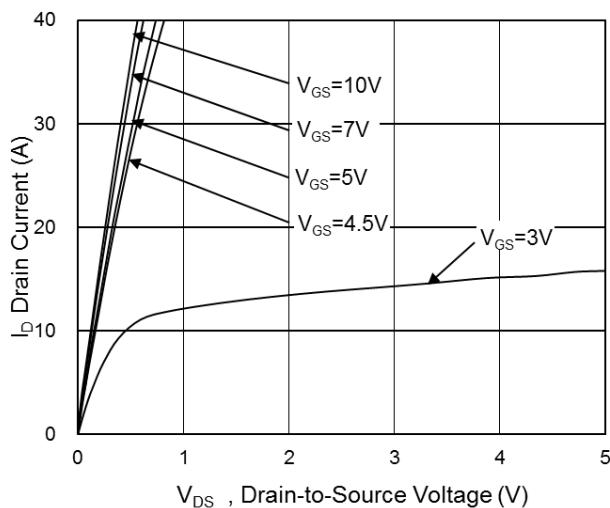
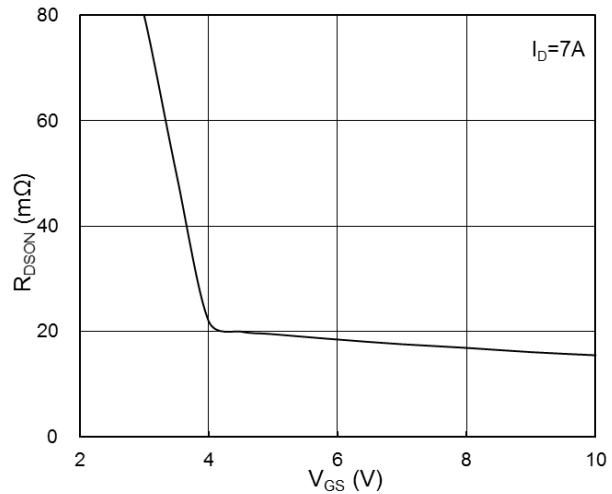
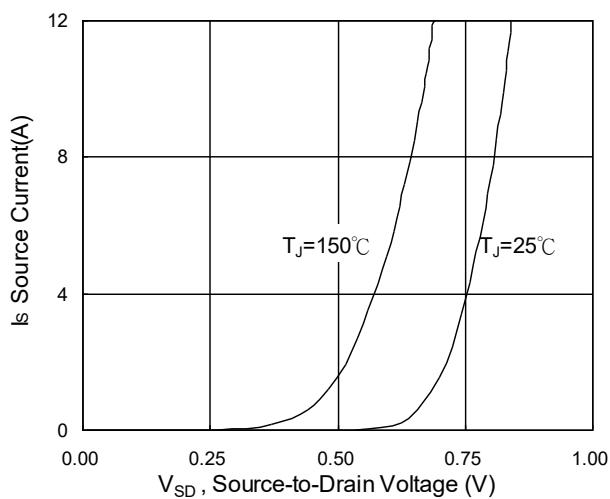
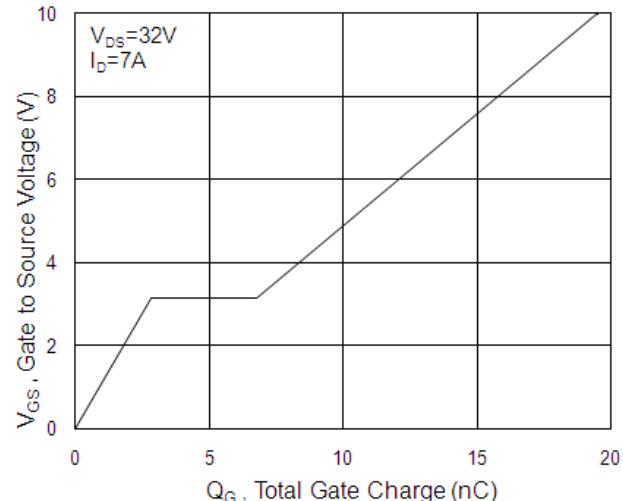
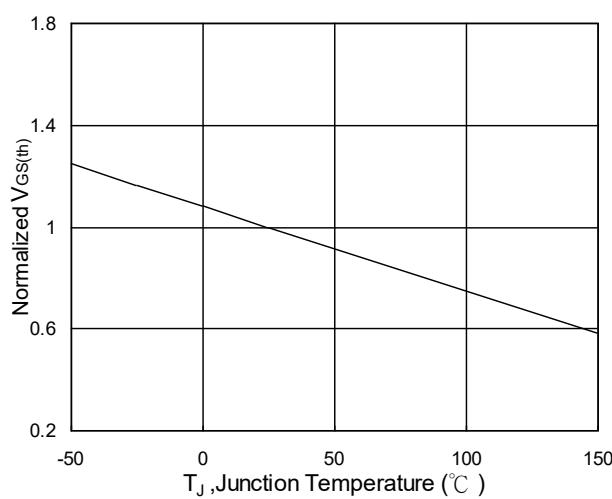
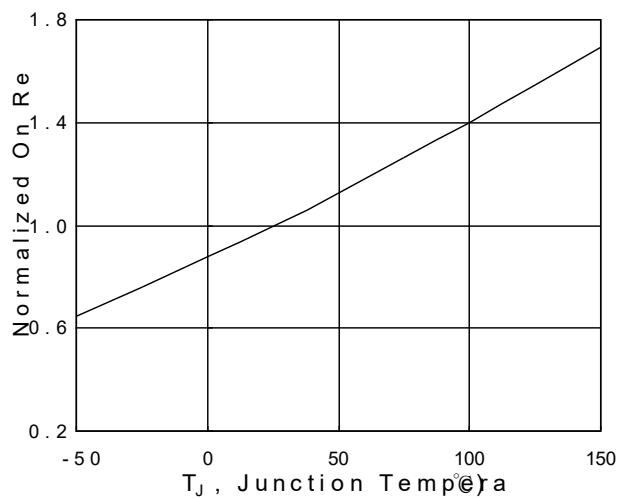
●Thermal Characteristics

PARAMETER	SYMBOL	MAX		UNIT
Thermal Resistance Junction-Ambient ¹ ($t \leq 10s$)	R_{thJA}	62.5		$^\circ C/W$
Soldering temperature,wavesoldering for 10s	T_{sold}	265		$^\circ C/W$

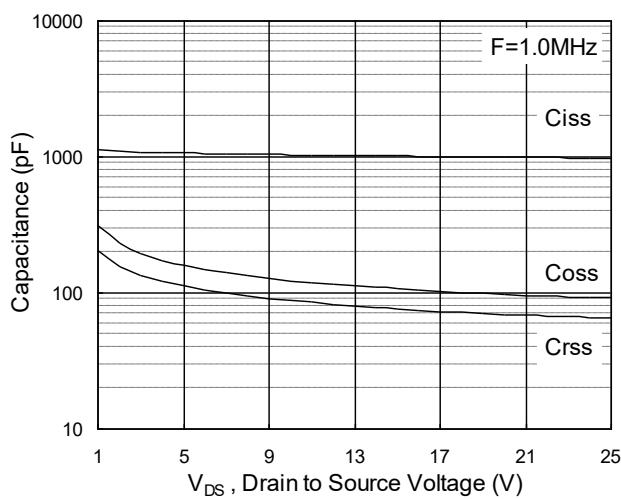
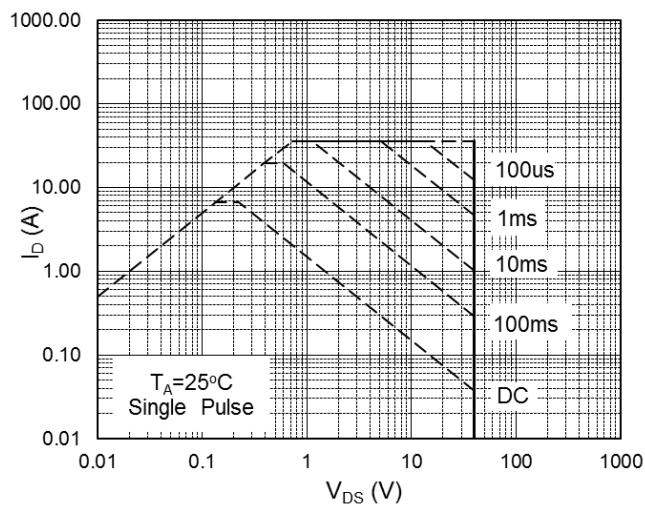
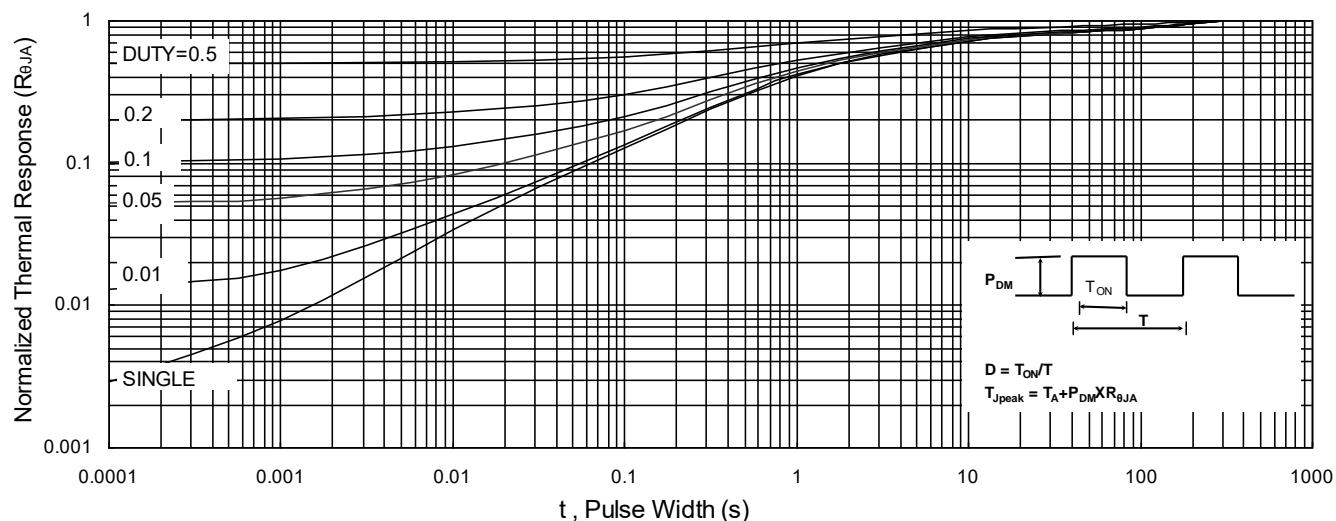
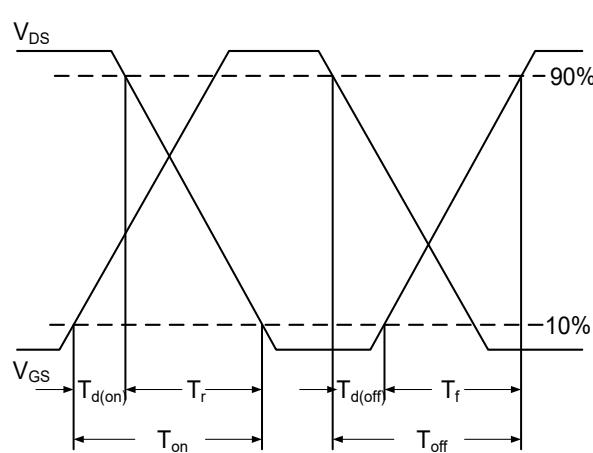
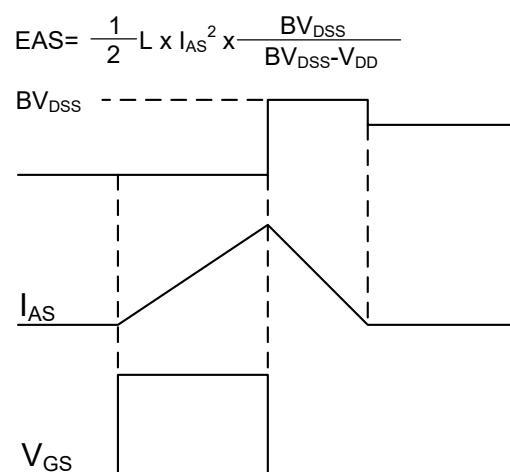
Notes:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper;
- 2.The data tested by Pulsed,Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$;
- 3.The EAS data shows Max. rating.The Test condition is $I_{AS}=4A, V_{DD}=15V, V_{GS}=10V$;
- 4.The Power Dissipation is limited by $150^\circ C$ junction temperature;
- 5.The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

- **Typical Characteristics**


Fig.1 Typical Output Characteristics

Fig.2 On-Resistance vs. G-S Voltage

Fig.3 Forward Characteristics of Reverse

Fig.4 Gate-Charge Characteristics

Fig.5 Normalized $V_{GS(th)}$ vs. T_J

Fig.6 Normalized $R_{DS(on)}$ vs. T_J

- **Typical Characteristics (CONT.)**


Fig.7 Capacitance

Fig.8 Safe Operating Area

Fig.9 Normalized Maximum Transient Thermal Impedance

Fig.10 Switching Time Waveform

Fig.11 Unclamped Inductive Switching Waveform

•Dimensions (SOP-8)

单位:毫米/UNIT: mm

SYMBOL	min	nom	max	SYMBOL	min	nom	max
A	4.80		5.00	C	1.30		1.50
A1	0.37		0.47	C1	0.55		0.75
A2		1.27		C2	0.55		0.65
A3		0.41		C3	0.05		0.20
B	5.80		6.20	C4	0.19	0.20	0.23
B1	3.80		4.00	D		1.05	
B2		5.00		D1	0.40		0.62

